NSN 6625-01-419-8132

Semiconductor Device Test Set - Page 1 of 1



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LIIU	Δ	DIIL	,auc	,,,,

Common test equipment

Inclosure Feature:

Multiple item w/housing

Test Type For Which Designed:

Parameter charactization of semiconductor devices

Purchase Description Identification:

1t110contract/f41608-94-c-0785

Shelf Life:

N/a

Unit Of Measure:

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Demilitarization:

Yes - demil/mli

Fiig:

T228-a